
Izdelki iz polprevodniških čipov - 5. del: Zahteve za informacije v zvezi z električno simulacijo (IEC 62258-5:2006)

(istoveten EN 62258-5:2006)

Semiconductor die products - Part 5: Requirements for information concerning electrical simulation (IEC 62258-5:2006)

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English version

Semiconductor die products
Part 5: Requirements for information
concerning electrical simulation
(IEC 62258-5:2006)

Produits de matrice de semi-conducteur
Partie 5: Exigences pour l'information
concernant la simulation électrique
(CEI 62258-5:2006)

Halbleiter-Chip-Erzeugnisse
Teil 5: Anforderungen für Angaben
hinsichtlich der elektrischen Simulation
(IEC 62258-5:2006)

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This European Standard was approved by CENELEC on 2006-09-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 47/1869/FDIS, future edition 1 of IEC 62258-5, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62258-5 on 2006-09-01.

This standard is to be used in conjunction with EN 62258-1 and EN 62258-2.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2007-06-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2009-09-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 62258-5:2006 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61691-2 NOTE Harmonized as EN 61691-2:2001 (not modified).

IEC 62014-1 NOTE Harmonized as EN 62014-1:2002 (not modified).

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 62258-1	- ¹⁾	Semiconductor die products Part 1: Requirements for procurement and use	EN 62258-1	2005 ²⁾
IEC 62258-2	- ¹⁾	Semiconductor die products Part 2: Exchange data formats	EN 62258-2	2005 ²⁾

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¹⁾ Undated reference.

²⁾ Valid edition at date of issue.

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INTERNATIONAL STANDARD

IEC 62258-5

First edition
2006-08

Semiconductor die products –

Part 5: Requirements for information concerning electrical simulation

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CONTENTS

FOREWORD.....	3
INTRODUCTION.....	5
1 Scope.....	6
2 Normative references.....	6
3 Terms and definitions.....	6
4 General.....	6
5 Requirements for information on electrical simulation models.....	7
5.1 Information on the electrical simulation model.....	7
5.2 Information on device connectivity.....	8
5.3 Information on the timing simulation model.....	8
5.4 Information on connection redistribution.....	8
5.5 Information on package terminals.....	9
Annex A (informative) Supporting information.....	10
Bibliography.....	12

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SIST EN 62258-5:2007

<https://standards.iteh.ai/catalog/standards/sist/459cdb1c-7125-48da-ba53-47c63419d32c/sist-en-62258-5-2007>

INTERNATIONAL ELECTROTECHNICAL COMMISSION

SEMICONDUCTOR DIE PRODUCTS –**Part 5: Requirements for information
concerning electrical simulation**

FOREWORD

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International Standard IEC 62258-5 has been prepared by IEC technical committee 47: Semiconductor devices.

This standard should be read in conjunction with IEC 62258-1 and IEC 62258-2.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/1869/FDIS	47/1882/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.